

Notice of References Cited	Application/Control No. 09/918,783	Applicant(s)/Patent Under Reexamination JENG ET AL.	
	Examiner Joseph P. Hirl	Art Unit 2121	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kishan Mehrotra et al, Elements of Artificial Neural Networks, 1997, MIT Press, 136-139
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	W	Raymond J. Madachy, System Dynamics Modeling of an Inspection-Based Process, 1996, IEEE, 376-386
	X	Jay W. Forrester, System Dynamics, System Thinking and Soft OR, 1994, MIT, 1-14

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.